

Notice of References Cited	Application/Control No. 10/517,257		Applicant(s)/Patent Under Reexamination HAQ ET AL.	
	Examiner ROBERT VETERE		Art Unit 1792	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,983,244	01-1991	Murakami et al.	156/224
*	B	US-5,780,101	07-1998	Nolan et al.	427/216
*	C	US-7,014,737	03-2006	Harutyunyan et al.	204/158.2
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO03/008331	01-2003	WIPO	KIM	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Setlur et al., Appl. Phys. Lett. 69 (3), p. 345 (1996).
*	V	Oku et al., Microelectronic Engr., 51-52, p. 51 (2000).
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.